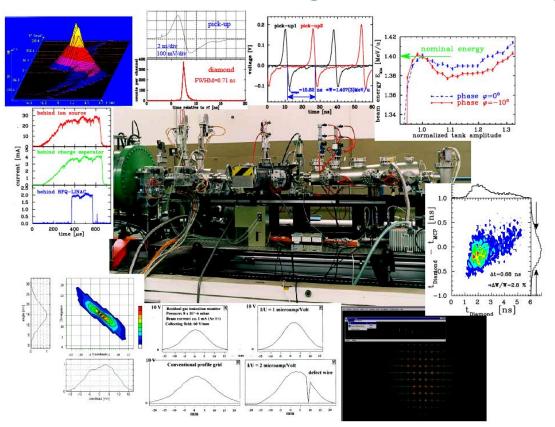


Beam Diagnostics and Instrumentation

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Demands on Beam Diagnostics



Diagnostics is the 'sensory organs' for the beam.

It deals with <u>real</u> beams in <u>real</u> technical installations including all imperfections.

Three types of demands lead to different installations:

- ➤ Quick, non-destructive measurements leading to a single number or simple plots
 Used as a check for online information. Reliable technologies have to be used

 Example: Current measurement by transformers
- ➤ Instruments for daily check, malfunction diagnosis and wanted parameter variation *Example*: Profile measurement, in many cases 'intercepting' i.e destructive to the beam
- ➤ Complex instruments for severe malfunctions, accelerator commissioning & development
 The instrumentation might be destructive and complex

 Example: Emittance determination

General usage of beam instrumentation:

- Monitoring of beam parameters for operation, beam alignment, acc. development.....
- ➤ Instruments for automatic, active beam control

Example: Closed orbit feedback using position measurement by BPMs

Non-destructive ('non-intercepting') methods are preferred:

- > The beam is not influenced
- ➤ The instrument is not destroyed

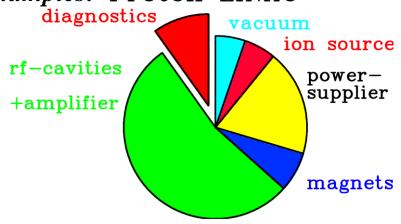
The Role of Beam Diagnostics



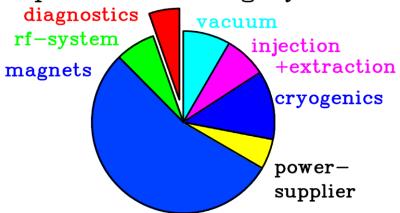
The cost of diagnostics is about 3 to 10 % of the total facility cost:

- $\geq \approx 3$ % for large accelerators *or* accelerators with standard technologies
- > 10% for versatile accelerators *or* novel accelerators and technologies.

Cost Examples: Proton LINAC



Super-conducting synchr.



The amount of man-power is about 10 to 20 %:

- > very different physics and technologies are applied
- technologies have to be up-graded, e.g. data acquisition and analysis
- > accelerator improvement calls for new diagnostic concepts.

Relevant physical Processes for Beam Diagnostics



- **Electro-magnetic influence by moving charges:**
 - \rightarrow <u>Physics</u>: classical electro-dynamics. <u>Technique</u>: *U* and *I* meas., low & high frequencies *Examples*: Faraday cups, beam transformers, pick-ups
- **Emission of photon by accelerated charges: (only for high relativistic electrons and p)**
 - → <u>Physics</u>: classical electro-dynamics. <u>Technique</u>: optical techniques (from visible to x-ray) *Example*: Synchrotron radiation monitors
- **➤** Interaction of particles with photons:
 - → <u>Physics</u>: optics, lasers. <u>Technique</u>: optical techniques, particle detectors Examples: laser scanners, short bunch length measurement, polarimeters
- **Coulomb interaction of charged particles with matter:**
- → <u>Physics</u>: atomic and solid state physics. <u>Technique</u>: *I* meas., optics, particle detectors *Examples*: scintillators, viewing screens, ionization chambers, residual gas monitors
- > Nuclear- or elementary particle physics interactions:
 - → <u>Physics</u>: nuclear physics. <u>Technique</u>: particle detectors Examples: beam loss monitors, polarimeters, luminosity monitors
- > And of cause accelerator physics for proper instrumentation layout.
- Beam diagnostics deals with the full spectrum of physics and technology,
- ⇒ this calls for experts on all these fields and is a challenging task!



Beam Quantities and their Diagnostics I

LINAC & transport lines: Single pass ↔ **Synchrotron:** multi pass

Electrons: always relativistic \leftrightarrow **Protons/Ions:** non-relativistic for $E_{kin} < 1$ GeV/u

Depending on application: Low current ↔ high current

Overview of the most commonly used systems:

| Beam quantity | | LINAC & transfer line | Synchrotron |
|--|---------|----------------------------|----------------------------|
| Current I | General | Transformer, dc & ac | Transformer, dc & ac |
| | | Faraday Cup | |
| | Special | Particle Detectors | Pick-up Signal (relative) |
| Profile x _{width} | General | Screens, SEM-Grids | Ionization Profile Monitor |
| · · · · · · · · · · · · · · · · · · · | | Wire Scanners, OTR Screen | Wire Scanner, |
| | | | Synchrotron Light Monitor |
| | Special | MWPC, Fluorescence Light | |
| Position x_{cm} | General | Pick-up (BPM) | Pick-up (BPM) |
| | Special | Using position measurement | |
| Transverse Emittance ε_{trans} | General | Slit-grid | Ionization Profile Monitor |
| i. u.i.s | | Quadrupole Variation | Wire Scanner |
| | Special | Pepper-Pot | Transverse Schottky |



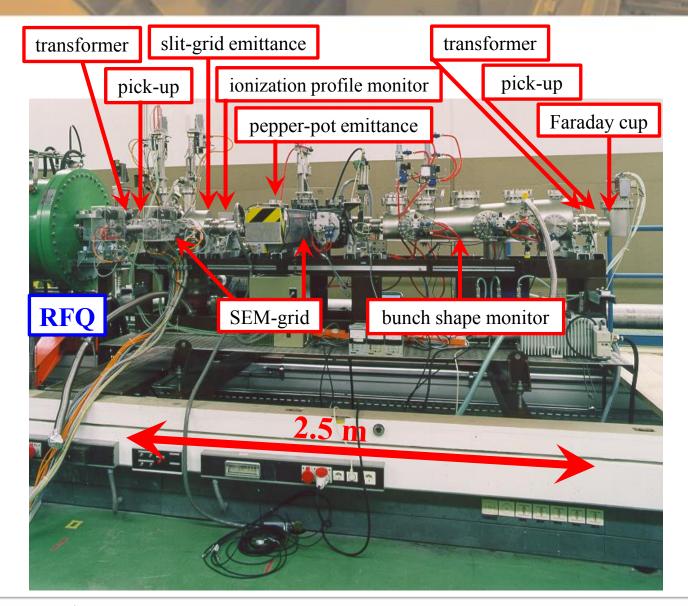
Beam Quantities and their Diagnostics II

| Beam quantity | | LINAC & transfer line | Synchrotron |
|-----------------------------------|---------|---------------------------------------|------------------------------|
| Bunch Length Δφ | General | Pick-up | Pick-up |
| | | | Wall Current Monitor |
| | Special | Secondary electrons arrival | Streak Camera |
| | | Electro-optical laser mod. | Electro-optical laser mod. |
| Momentum p and | General | Pick-ups (Time-of-Flight) | Pick-up (e.g. tomography) |
| Momentum Spread <i>∆p/p</i> | Special | Magnetic Spectrometer | Schottky Noise Spectrum |
| Longitudinal Emittance | General | Buncher variation | |
| [€] long | Special | Magnetic Spectrometer | Pick-up & tomography |
| Tune and Chromaticity Q , ξ | General | | Exciter + Pick-up |
| | Special | | Transverse Schottky Spectrum |
| Beam Loss r _{loss} | General | Particle Detectors | |
| Polarization P | General | Particle Detectors | |
| | Special | Laser Scattering (Compton scattering) | |
| Luminosity L | General | Particle Detectors | |

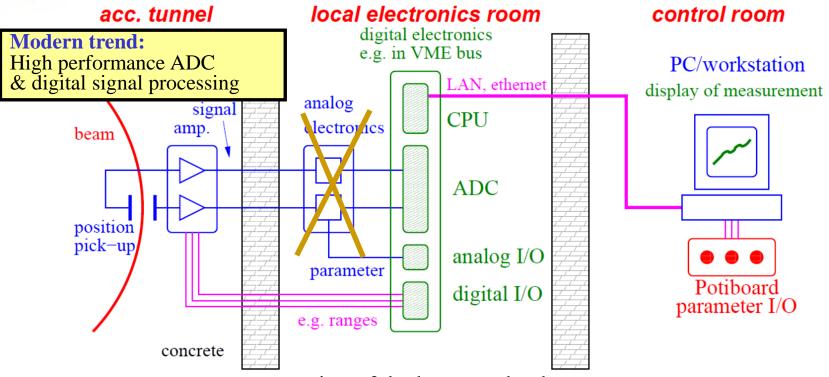
- Destructive and non-destructive devices depending on the beam parameter.
- ➤ Different techniques for the same quantity ↔ Same technique for the different quantities.

Remark: In most cases no diagnostics device installed inside the rf-cavities (except cyclotron)

Example: Diagnostics Bench for the Commissioning of an RFQ



Typical Installation of a Diagnostics Device



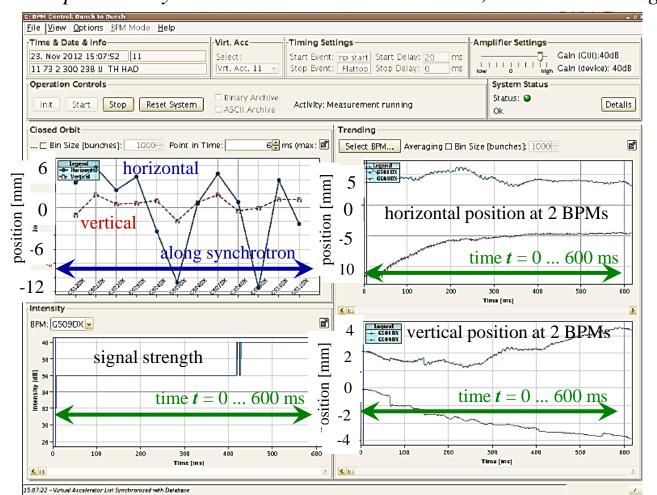
- \rightarrow action of the beam to the detector
- accelerator tunnel: → low noise pre-amplifier and first signal shaping
 - → analog treatment, partly combining other parameters
- local electronics room:
 - \rightarrow digitalization, data bus systems (GPIB, VME, cPCI, μ TCA...)
- → visualization and storage on PC farm control room:
 - → parameter setting of the beam and the instruments

Close Orbit Measurement with Beam Position Monitors BPM



Single bunch position averaged over 1000 bunches \rightarrow closed orbit with ms time steps. It differs from ideal orbit by misalignments of the beam or components.

Example: GSI-synchrotron at two BPM locations, 1000 turn average during acceleration:



Closed orbit:

Beam position averaged over many turns (i.e. betatron oscillations).

The result helps to align the accelerator!

Some device parameters are shown to prove functionality.

Outline of the Lecture

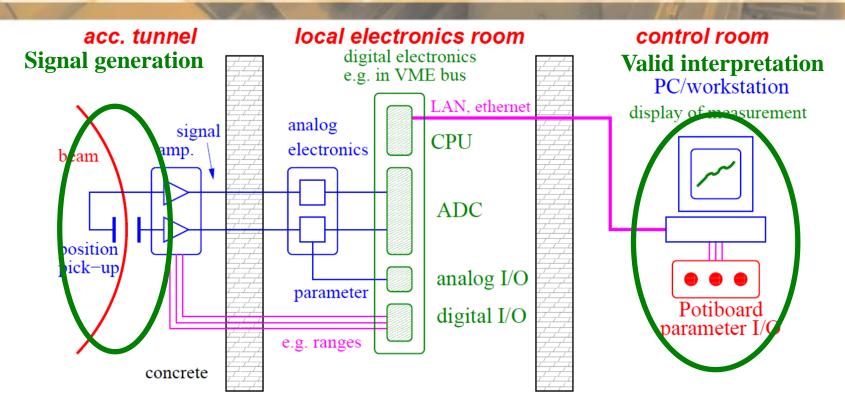


The ordering of the subjects is oriented by the beam quantities:

- **Current measurement:** Transformers, cups, particle detectors
- **Profile measurement:** Various methods depending on the beam properties
- ➤ Transverse emittance measurement: Destructive devices, determination by linear transformations
- ➤ Pick-ups for bunched beams: Principle and realization of rf pick-ups, closed orbit and tune measurements
- ➤ Measurement of longitudinal parameters: Beam energy with pick-ups, time structure of bunches for low and high beam energies, longitudinal emittance
- **Beam loss detection:** Secondary particle detection for optimization and protection
- It will be discussed: The action of the beam to the detector, the design of the devices, generated raw data, partly analog electronics, results of the measurements.
- It will not be discussed: Detailed signal-to-noise calculations, analog electronics, digital electronics, data acquisition and analysis, online and offline software....
- General: Standard methods and equipment for stable beams with moderate intensities.

Goal of the Lecture





The goal of the lecture should be:

- **▶** Understanding the signal generation of various device
- Showing examples for real beam behavior
- Enabling a correct interpretation of various measurements.